



PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE CITATION

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Sheet 1 of 1

ATTORNEY DOCKET NO.	SERIAL NO.
9319A-000222 09/871,600	
APPLICANT	
ARAI, et al	·
FILING DATE	GROUP
5/31/2001	1755

U.S. P	ATEN	T DO	CUMENTS			_	•
Ref. Desig.	Examination		Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
1.	2	Z	5,872,501	2/16/1999	Hamano et al		

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Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes No
1.	SL	10-53844	2/24/1998	JAPAN		Abstract

OTHE	R DOCUME	NTS (including Author, Title, Date, Pertinent Pages, etc.)	
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FORM HDP-1449 (Based on Form PTO-1449)

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Sheet 1 of 1

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ATTORNEY DOCKET No.	SERIAL NO.		
9319A-000222 09/871,600			
APPLICANT			
Akira ARAI et al	,		
FILING DATE	GROUP		
May 31, 2001 1755			

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1-20-2002

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